

CLAIMS:

1. A method for producing high purity tantalum comprising the steps of: purifying K₂TaF₇ by a dissolution process; reacting purified K₂TaF₇ with a reducing agent to produce tantalum powder;

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reacting said tantalum powder with iodine in a container.

- 2. A method according to claim 1, wherein HF or a mixture of HF and H₂SO₄ is used in the dissolution of K₂TaF₇.
- 3. A method according to claim, wherein a solution containing KC1 is used to precipitate said K₂TaF₇ from the solution
- 4. A method according to claim 1, wherein Nb and other metallic impurities in said K₂TaF₇ are reduced to levels lower than about 20 ppm, by weight.
- 5. A method according to claim 1, wherein W and Mo in said K₂TaF₇ are reduced to less than about 1 ppm, by weight.
 - 6. A method according to claim 1, wherein said reducing agent is sodium.
- 7. A method according to claim 1, wherein said container has a reactant-contacting surface comprising a metal more electrochemically noble than tantalum according to the chloride electromotive series.
- 8. A method according to claim 7, wherein said reactant-contacting surface comprises molybdenum, tungsten or an alloy of molybdenum and tungsten.
- 9. A method according to claim 1, further comprising electron beam melting said tantalum to produce a high purity tantalum ingot.
 - 10. A method for producing high purity tantalum comprising reacting impure tantalum with iodine gas in a container and decomposing tantalum iodides on a filament.

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1 A method according to claim 10 wherein said container has a reactant-11. contacting surface comprising a metal more electrochemically noble than tantalum according to the chloride electromotive series. 5 12. A method according to claim 11 wherein said reactant-contacting surface comprises molybdenum, tungsten or an alloy of molybdenum and tungsten. A method according to claim 10 wherein said filament comprises tantalum. 13. 10 A method according to claim 10 further comprising electron-beam melting 14. said tantalum to form a high-purity tantalum ingot. High purity tantalum comprising tantalum and less than about 500 ppm, by 15. weight, total metallic impurities. HOOUNDO HOO HA High purity tantalum comprising less than about 50 ppm, by weight, tungsten 16. or molybdenum. High purity tantalum comprising less than about 20 ppm, by weight, tungsten 17. or molybdenum. High purity tantalum comprising less than about 5 ppm, by weight, each of 18. Uī tungsten and molybdenum. TU 25 High purity tantalum comprising less than 20 ppm, by weight, total of 19. niobium, molybdenum and tungsten. High purity tantalum comprising tantalum and less than 5 ppm, by weight, 20. total of niobium, molybdenum and tungsten 30 A sputtering target comprising high purity titanium according to claim 15. 21. A sputtering target comprising high purity titanium according to claim 16. 22.

A sputtering target comprising high purity titanium according to claim 17.

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	24.	A sputtering target comprising high purity titanium according to claim 18.
5	25.	A sputtering target comprising high purity titanium according to claim 19.
	26.	A thin film produced by a spattering target according to claim 15.
	27.	A thin film produced by a sputtering target according to claim 16.
10	28.	A thin film produced by a sputtering target according to claim 17.
	29.	A thin film produced by a sputtering target according to claim 18.
直5	. 30.	A thin film produced by a sputtering target according to claim 19.
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